

## عنوان مقاله:

Designing sampling plans for the truncated life test

## محل انتشار:

اولین کنفرانس بین المللی بهینه سازی سیستم ها و مدیریت کسب و کار (سال: 1396)

تعداد صفحات اصل مقاله: 8

## نویسنده:

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## خلاصه مقاله:

Truncated life test is usually applied for reducing the experiment time. In this paper, repetitive group sampling (RGS) plan and double sampling (DS) plan are proposed for the truncated life test of the items having Weibull distribution. In RGS plan, the submitted lot is accepted if the number of defectives is smaller than an acceptance criteria, it is rejected if the number of defectives is larger than a rejection criteria or the process is repeated otherwise. In the DS plan, first, a sample is taken from the lot and if the number of defectives is larger than a specified criteria then the submitted lot is rejected. If the number of defectives is smaller than another criteria, the submitted lot is accepted or otherwise another sample is taken and the final decision is made based on the results of both samples. The application of these two sampling plans are illustrated in the industry using a real example. Finally results of the comparison study indicate that the DS plan leads to the smaller ASN in comparison with the RGS, but the DS plan has no feasible solution in some cases

## کلمات کلیدی:

truncated life test; lifetime; repetitive sampling plan; double sampling plan

## لینک ثابت مقاله در پایگاه سیویلیکا:

<https://civilica.com/doc/674487>

